



**NSAI**  
Standards

Irish Standard  
I.S. EN 62132-8:2012

Integrated circuits - Measurement of  
electromagnetic immunity -- Part 8:  
Measurement of radiated immunity - IC  
stripline method (IEC 62132-8:2012  
(EQV))

## I.S. EN 62132-8:2012

*Incorporating amendments/corrigenda issued since publication:*

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**Integrated circuits -  
Measurement of electromagnetic immunity -  
Part 8: Measurement of radiated immunity -  
IC stripline method  
(IEC 62132-8:2012)**

Circuits intégrés -  
Mesure de l'immunité électromagnétique -  
Partie 8: Mesure de l'immunité rayonnée -  
Méthode de la ligne TEM à plaques pour  
circuit intégré  
(CEI 62132-8:2012)

Integrierte Schaltungen -  
Messung der elektromagnetischen  
Störfestigkeit -  
Teil 8: Messung der Störfestigkeit bei  
Einstrahlungen -  
IC-Streifenleiterverfahren  
(IEC 62132-8:2012)

This European Standard was approved by CENELEC on 2012-08-10. CENELEC members are bound to comply with the CEN/CENELEC Internal Regulations which stipulate the conditions for giving this European Standard the status of a national standard without any alteration.

Up-to-date lists and bibliographical references concerning such national standards may be obtained on application to the CEN-CENELEC Management Centre or to any CENELEC member.

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**CENELEC**

European Committee for Electrotechnical Standardization  
Comité Européen de Normalisation Electrotechnique  
Europäisches Komitee für Elektrotechnische Normung

**Management Centre: Avenue Marnix 17, B - 1000 Brussels**

**I.S. EN 62132-8:2012**

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**Foreword**

The text of document 47A/882/FDIS, future edition 1 of IEC 62132-8, prepared by SC 47A, "Integrated circuits", of IEC TC 47, "Semiconductor devices" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62132-8:2012.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2013-05-10
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2015-08-10

This standard is to be used in conjunction with EN 62132-1.

Attention is drawn to the possibility that some of the elements of this document may be the subject of patent rights. CENELEC [and/or CEN] shall not be held responsible for identifying any or all such patent rights.

**Endorsement notice**

The text of the International Standard IEC 62132-8:2012 was approved by CENELEC as a European Standard without any modification.

## Annex ZA (normative)

### Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE When an international publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 60050	Series	International Electrotechnical Vocabulary	-	-
IEC 61000-4-20	2010	Electromagnetic compatibility (EMC) - Part 4-20: Testing and measurement techniques - Emission and immunity testing in transverse electromagnetic (TEM) waveguides	EN 61000-4-20	2010
IEC 62132-1	2006	Integrated circuits - Measurement of electromagnetic immunity, 150 kHz to 1 GHz - Part 1: General conditions and definitions	EN 62132-1 + corr. November	2006 2006

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## INTERNATIONAL ELECTROTECHNICAL COMMISSION

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**INTEGRATED CIRCUITS –  
MEASUREMENT OF ELECTROMAGNETIC IMMUNITY –**
**Part 8: Measurement of radiated immunity –  
IC stripline method**

## FOREWORD

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International Standard IEC 62132-8 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices.

The text of this standard is based on the following documents:

FDIS	Report on voting
47A/882/FDIS	47A/886/RVD

Full information on the voting for the approval of this standard can be found in the report on voting indicated in the above table.

This publication has been drafted in accordance with the ISO/IEC Directives, Part 2.

This part of IEC 62132 is to be read in conjunction with IEC 62132-1.

A list of all the parts in the IEC 62132 series, published under the general title *Integrated circuits – Measurement of electromagnetic immunity*, can be found on the IEC website.

Future standards in this series will carry the new general title as cited above. Titles of existing standards in this series will be updated at the time of the next edition.

The committee has decided that the contents of this publication will remain unchanged until the stability date indicated on the IEC web site under "<http://webstore.iec.ch>" in the data related to the specific publication. At this date, the publication will be

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- withdrawn,
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